

<b>Notice of References Cited</b>	Application/Control No. 10/531,039		Applicant(s)/Patent Under Reexamination KENNEY ET AL.	
	Examiner JOHN J. LEE		Art Unit 2618	Page 1 of 1

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*	B	US-6,298,092	10-2001	Heath et al.	455/101
*	C	US-6,377,819	04-2002	Gesbert et al.	455/562.1
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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